

U.S. DEPT. OF COMMERCE PATENT AND TRADEMARK OFFICE

Page 1 of 1

Form PTO-1449 LIST OF PRIOR ART CITED BY APPLICANT <i>(Use several sheets if necessary)</i>			ATTORNEY DOCKET NO. RSW920050159US1		SERIAL NO. Not Assigned	
			APPLICANT Dalal et al.			
			FILING DATE November 4, 2005		GROUP ART UNIT Not Assigned	

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	PUBLICATION DATE	INVENTOR NAME	CLASS/SUBCLASS	FILING DATE	
/H.Y./	AA	6,167,563	Dec. 26, 2000	Fontana et al.	717/1	Sep. 17, 1998
/H.Y./	AB	6,167,564	Dec. 26, 2000	Fontana et al.	717/1	Sep. 17, 1998
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FOREIGN PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	PUBLICATION DATE	COUNTRY	CLASS/SUBCLASS	TRANSLATION YES NO	

OTHER PRIOR ART <i>(including author, title, date, pertinent page, etc.)</i>	
/H.Y./	AF Spanoudakis, "Plausible and Adaptive Requirement Traceability Structures", ACM Digital Library, 2002, pp. 135-142
/H.Y./	AG Mason et al., "On Structuring Formal, Semi-Formal and Informal Data to Support Traceability in Systems Engineering Environments", ACM Digital Library, 2004, pp. 642-651.
/H.Y./	AH Conwell et al., "Capability Maturity Models Support of Modeling and Simulation Verification, Validation, and Accreditation", Proceedings of the 2000 Winter Simulation Conference, ACM Digital Library, 2000, pp. 819-828
/H.Y./	AI Wu et al., "ATRAM: An Analysis Tool of Requirement and Architecture Management", 2003 IEEE International Conference on Systems, Man and Cybernetics, Vol. 3, Piscataway, NJ, USA, pp. 2654-2660.
/H.Y./	AJ Gills et al., "Tracelt: Enabling Extended Use of a Traceability Tool within Software Development Project." <u>BalticDB&IS 2002</u> : pp.147-158

RELATED PATENT APPLICATIONS				
EXAMINER INITIAL	APPLICATION NO./ ATTY. DOCKET NO.	APPLICANT	TITLE	FILING DATE

DATE CONSIDERED 01/12/2009	EXAMINER /Himanshu Yadav/
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